

**Search Notes**

Application/Control No.

09/784,722

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

TANG ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
370	392	1/30/2006	DB
709	238	1/30/2006	DB
370	400	1/30/2006	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	1/30/2006	DB